Characterisation of prototype SiGe monolithic pixel detectors for the TT-PET project

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FACULTÉ DES SCIENCES Section de physique



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- TT-PET Project
- Scanner Overview
- Monolithic Chip
- Test beam characterization
- TOF simulation
- Prototype-0

The TT-PET Project

> 3-year project to produce a PET Scanner for small animals based on silicon detector technology, insertable in an MRI machine and with 30ps RMS time resolution. The project started in March 2016.

- > Collaborating institutes:
 - > University of Geneva
 - > University of Bern
 - > Hôpital cantonale de Genève
 - > INFN of Roma Tor Vergata
 - CERN

TSPO PET/MRI (Inflammation model in mouse brain)



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Why use Time-of-Flight?

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- Adding Time-of-Flight information to a PET scan can dramatically increase its performance!
- It is used to localize the source along the line of flight
- It leads to much lower noise, which can be used to increase image quality or decrease radiation dose to the patient



Scanner Overview

- Designed to fit inside removable RF-Coil for nanoScan 3T
- ➢ 16 sensitive towers
- > 16 cooling blocks: ceramic/ 3d printed
- Exterior carbon fiber support and cooling pipes not shown
- > Inner radius: 65mm> Outer radius: 80mm
- > Total Pixel channels: 1,413,120
- Pixel size: 500x500µm²



Scanner Overview

- Sensitive towers composed of many layers of lead, flex circuit, and monolithic pixels sensors
- > 1 tower = 60 sensitive detection layers
- > Sampling style detector
- Geometrical acceptance is maximized using step like structure
- Longer data cables connect to the DAQ outside of the RF-Coil

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50µm Lead Foil

> 500x500 μ m pixels

Gamma Ray

- > Baseline option: bump bond monolithic chip to flex circuit
- Second option: stack multiple chips on top of each other and wire bond together (same process as inside memory chips)



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Event Rate and Data Pressure

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- Readout designed for 50MBq source
 - > 19.2 MHz single hit rate
 - > 5 MHz possible coincidences
 - > 1.2 MHz real coincidences
- > System designed for scalability
 - Custom Designed Tower Control board to control one Tower
 - > Commercial components used where possible
 - CERN VLDB board (GBTx) used to multiplex multiple tower control DAQ boards





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- > Very high granularity, with access to DOI and TOF information for every hit
- > Faster signals mean ability to have high-precision timing measurements
- The scanner can be designed to be compatible with an MRI scanner, providing combined MRI-PET images
- > On the other hand...
- > The mechanics of the scanner are really complex (especially the data flex)
- > There are a very large number of channels, so the data acquisition scheme is critical
- \succ Every channel must be calibrated \rightarrow very long procedure

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- First Monolithic Test ASIC
- SG13S SiGe BiCMOS process from IHP microelectronics (130nm)
- Very High CMOS resistivity suitability $(1k\Omega cm)$
- > Test custom guard ring design and qualify HV tolerance (180V)
- 1 small pixel 900x450µm² > 1 large pixel 900x900 μ m²
- Geometry type: n-in-p
- > ToF RMS (mips): 100ps



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Electronics placed outside of the pixel guard







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- Electronics placed outside of the pixel guard
- > SiGe pre-amplifier
 - > Amplifier rise time 1-2ns
 - Discriminator
 - Time-over-Threshold measurement





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- TT-PET Collaboration
- Scanner Overview
- Monolithic Chip
- Test beam characterization
- TOF simulation
- Other prototypes

Test beam setup

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- > 180 GeV/c pion beam used (CERN SPS beamline)
- > Particle telescope (Geneva FE-I4 telescope) used for tracking
- 2 Monolithic test chips operated at 180V (backside not metalized, and referenced to Gnd)
- > LGAD sensor used as final plane (timing reference)

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- > Overlap region (red dashed box)
- Only particle tracks that intersect this ROI are used
- > Upstream Sensor efficiency (99.79 ± 0.01)%
- Downstream efficiency (99.09 ± 0.04)%
- > No areas of large inefficiency





Charge Uniformity



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- > Amount of charge shown in ToT
- Drop in amount of charge collected around edges of pixel
- Non-uniform electric field near edges
- Sensor not thinned down to 100um and not backside metalised
- Aim for 2-3 V/um to maximise e⁻ carrier mobility



- > Tot distribution on left
- > Time-walk correction done using a polynomial fit
- Spread of the time-walk and SNR information used to estimate actual pre-amp peaking time <2ns (agree with our cadence simulations)</p>

ToF measurement



	Time resolution [ps]	
Pixel	w/o position correction	with position correction
Downstream Small	202.3 ± 0.8	167.7 ± 0.7
Upstream Small	219.0 ± 0.7	188.2 ± 0.6
Upstream Large	265 ± 1	212 ± 1

Despite lack of vital processing steps ToF no so far away from 100ps for MIP's expected

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Simple phantom simulation

- > Simple reconstruction (FBP)
- >10° events simulated
- Expected detector response included



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Prototype-0



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- A fully featured prototype was submitted in April 2017 (MPW run)
- > It has a smaller matrix (30 pixels) and a simplified readout scheme, but it's otherwise complete
- Low resistivity wafer first (check HV doesn't interfere with LV electronics
- It's useful to test integration issues (power delivery, crosstalk...)





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- > Delays in high resistivity delivery
- Thin wafers broke at backside metaisation and dicing stage
- A MPW runs per year, ~4 month process time
- HR backside metalised diced chips delivered last week
- > HV tested to work upto target 300V





Test setups





- DAQ software and firmware has already been developed
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- Continued to to be improved
- Additional power module for the each Tower control FPGA board has been completed
- Top left: Prototype-0 (red PCB) being tested at Bern
- Probe station used to characterize monolithic chips before being mounted on PCB's for testing (R&D)





Now that Prototype-0 HR has been delivered



- ToF / coincidence measurements will be performed in the coming weeks at Bern cyclotron using custom F18 phantom's
- ToF measurements using cyclotron 18 MeV proton beam
- CFRP support + protective skin going through final revisions





>Na22 ToF at Geneva University shortly

➢Final monolithic design submission expected Sept/October 2018

Thank You

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Questions?

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Backup



Why use Time-of-Flight?



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Conventional PET





TOF PET



Time resolution



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> Detector time resolution depends mostly on the amplifier performance.

$$\sigma_t = \frac{\sigma_V}{\frac{dV}{dt}} \cong \frac{t_{rise}}{Signal/_{Noise}}$$





Time-over-Threshold

 $\propto TOT_1$

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Preamplificator

Discriminator

Counter



 $\propto TOT_2$

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Event Rate and Data Pressure

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> Hit rate for a 50 MBq point source is still < 25kHz per layer



Geant4 Simulation

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